

## CD4094BC 8-Bit Shift Register/Latch with 3-STATE Outputs

### General Description

The CD4094BC consists of an 8-bit shift register and a 3-STATE 8-bit latch. Data is shifted serially through the shift register on the positive transition of the clock. The output of the last stage ( $Q_8$ ) can be used to cascade several devices. Data on the  $Q_8$  output is transferred to a second output,  $Q'_8$ , on the following negative clock edge.

The output of each stage of the shift register feeds a latch, which latches data on the negative edge of the STROBE input. When STROBE is HIGH, data propagates through the latch to 3-STATE output gates. These gates are enabled when OUTPUT ENABLE is taken HIGH.

### Features

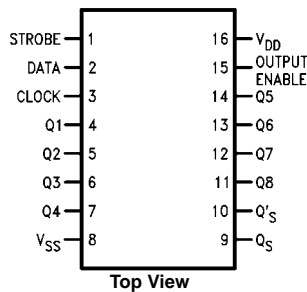
- Wide supply voltage range: 3.0V to 18V
- High noise immunity:  $0.45 V_{DD}$  (typ.)
- Low power TTL compatibility:
  - Fan out of 2 driving 74L or 1 driving 74LS
- 3-STATE outputs

### Ordering Code:

Order Number	Package Number	Package Description
CD4094BCWM	M16B	16-Lead Small Outline Intergrated Circuit (SOIC), JEDEC MS-013, 0.300" Wide
CD4094BCN	N16E	16-Lead Plastic Dual-In-Line Package (PDIP), JEDEC MS-001, 0.300" Wide

Devices also available in Tape and Reel. Specify by appending the suffix letter "X" to the ordering code.

### Connection Diagram



### Truth Table

Clock	Output Enable	Strobe	Data	Parallel Outputs		Serial Outputs	
				$Q_1$	$Q_N$	$Q_8$ (Note 1)	$Q'_8$
~	0	X	X	Hi-Z	Hi-Z	Q7	No Change
~	0	X	X	Hi-Z	Hi-Z	No Change	Q7
~	1	0	X	No Change	No Change	Q7	No Change
~	1	1	0	0	$Q_{N-1}$	Q7	No Change
~	1	1	1	1	$Q_{N-1}$	Q7	No Change
~	1	1	1	No Change	No Change	No Change	Q7

X = Don't Care  
~ = HIGH-to-LOW  
~ = LOW-to-HIGH

**Note 1:** At the positive clock edge, information in the 7th shift register stage is transferred to  $Q_8$  and  $Q'_8$ .



**Absolute Maximum Ratings**(Note 2)

(Note 3)

Supply Voltage ( $V_{DD}$ )	-0.5 to +18 $V_{DC}$
Input Voltage ( $V_{IN}$ )	-0.5 to $V_{DD} + 0.5 V_{DC}$
Storage Temperature Range ( $T_S$ )	-65°C to +150°C
Power Dissipation ( $P_D$ )	
Dual-In-Line	700 mW
Small Outline	500 mW
Lead Temperature ( $T_L$ )	
(Soldering, 10 seconds)	260°C

**Recommended Operating Conditions** (Note 3)

DC Supply Voltage ( $V_{DD}$ )	+3.0 to +15 $V_{DC}$
Input Voltage ( $V_{IN}$ )	0 to $V_{DD} V_{DC}$
Operating Temperature Range ( $T_A$ )	-55°C to +125°C

**Note 2:** "Absolute Maximum Ratings" are those values beyond which the safety of the device cannot be guaranteed; they are not meant to imply that the devices should be operated at these limits. The tables of "Recommended Operating Conditions" and "Electrical Characteristics" provide conditions for actual device operation.

**Note 3:**  $V_{SS} = 0V$  unless otherwise specified.

**DC Electrical Characteristics** (Note 3)

Symbol	Parameter	Conditions	55°C		+25°C			+125°C		Units	
			Min	Max	Min	Typ	Max	Min	Max		
$I_{DD}$	Quiescent Device Current	$V_{DD} = 5.0V$ $V_{DD} = 10V$ $V_{DD} = 15V$		5.0 10 20				5.0 10 20		150 300 600	$\mu A$
$V_{OL}$	LOW Level Output Voltage	$V_{DD} = 5.0V$ $V_{DD} = 10V$ $ I_O  \leq 1.0 \mu A$ $V_{DD} = 15V$		0.05 0.05 0.05		0 0 0		0.05 0.05 0.05		0.05 0.05 0.05	V
$V_{OH}$	HIGH Level Output Voltage	$V_{DD} = 5.0V$ $V_{DD} = 10V$ $ I_O  \leq 1 \mu A$ $V_{DD} = 15V$	4.95 9.95 14.95		4.95 9.95 14.95	5.0 10.0 15.0		4.95 9.95 14.95			V
$V_{IL}$	LOW Level Input Voltage	$V_{DD} = 5.0V, V_O = 0.5V$ or 4.5V $V_{DD} = 10V, V_O = 1.0V$ or 9.0V $V_{DD} = 15V, V_O = 1.5V$ or 13.5V		1.5 3.0 4.0				1.5 3.0 4.0		1.5 3.0 4.0	V
$V_{IH}$	HIGH Level Input Voltage	$V_{DD} = 5.0V, V_O = 0.5V$ or 4.5V $V_{DD} = 10V, V_O = 1.0V$ or 9.0V $V_{DD} = 15V, V_O = 1.5V$ or 13.5V	3.5 7.0 11.0		3.5 7.0 11.0			3.5 7.0 11.0			V
$I_{OL}$	LOW Level Output Current (Note 4)	$V_{DD} = 5.0V, V_O = 0.4V$ $V_{DD} = 10V, V_O = 0.5V$ $V_{DD} = 15V, V_O = 1.5V$	0.64 1.6 4.2		0.51 1.3 3.4	0.88 2.25 8.8		0.36 0.9 2.4			mA
$I_{OH}$	HIGH Level Output Current (Note 4)	$V_{DD} = 5.0V, V_O = 4.6V$ $V_{DD} = 10V, V_O = 9.5V$ $V_{DD} = 15V, V_O = 13.5V$	-0.64 -1.6 -4.2		-0.51 -1.3 -3.4	0.88 2.25 8.8		-0.36 -0.9 -2.4			mA
$I_{IN}$	Input Current	$V_{DD} = 15V, V_{IN} = 0V$ $V_{DD} = 15V, V_{IN} = 15V$		-0.1 0.1				-0.1 0.1		-1.0 1.0	$\mu A$
$I_{OZ}$	3-STATE Output Leakage Current	$V_{DD} = 15V, V_{IN} = 0V$ or 15V		0.3				$\pm 0.3$		$\pm 9$	$\mu A$

**Note 4:**  $I_{OH}$  and  $I_{OL}$  are tested one output at a time.

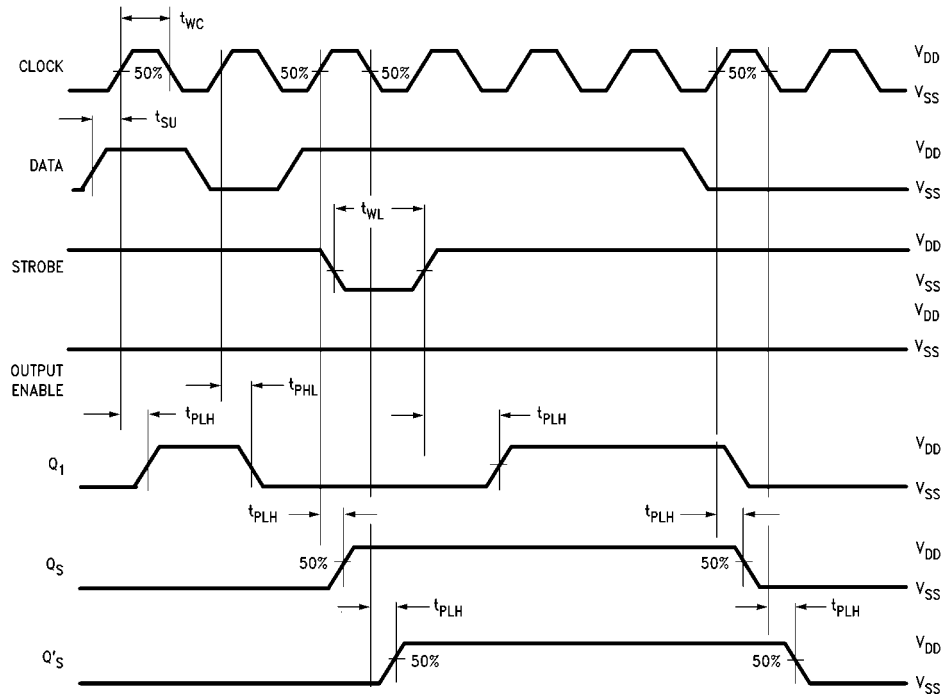
### AC Electrical Characteristics (Note 5)

 $T_A = 25^\circ\text{C}$ ,  $C_L = 50\text{ pF}$ 

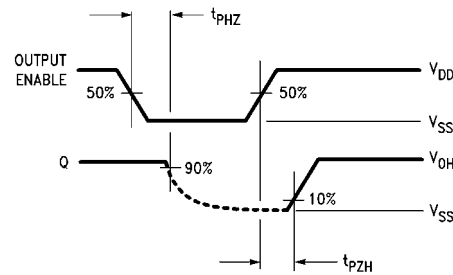
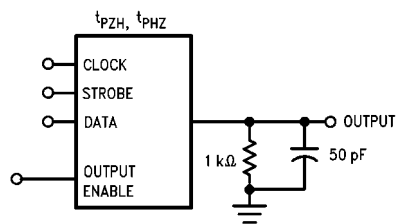
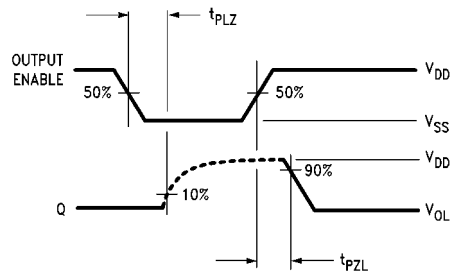
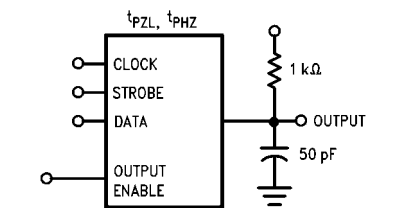
Symbol	Parameter	Conditions	Min	Typ	Max	Units
$t_{PHL}$ , $t_{PLH}$	Propagation Delay Clock to $Q_S$	$V_{DD} = 5.0\text{V}$		300	600	ns
		$V_{DD} = 10\text{V}$		125	250	
		$V_{DD} = 15\text{V}$		95	190	
$t_{PHL}$ , $t_{PLH}$	Propagation Delay Clock to $Q'_S$	$V_{DD} = 5.0\text{V}$		230	460	ns
		$V_{DD} = 10\text{V}$		110	220	
		$V_{DD} = 15\text{V}$		75	150	
$t_{PHL}$ , $t_{PLH}$	Propagation Delay Clock to Parallel Out	$V_{DD} = 5.0\text{V}$		420	840	ns
		$V_{DD} = 10\text{V}$		195	390	
		$V_{DD} = 15\text{V}$		135	270	
$t_{PHL}$ , $t_{PLH}$	Propagation Delay Strobe to Parallel Out	$V_{DD} = 5.0\text{V}$		290	580	ns
		$V_{DD} = 10\text{V}$		145	290	
		$V_{DD} = 15\text{V}$		100	200	
$t_{PHZ}$	Propagation Delay HIGH Level to HIGH Impedance	$V_{DD} = 5.0\text{V}$		140	280	ns
		$V_{DD} = 10\text{V}$		75	150	
		$V_{DD} = 15\text{V}$		55	110	
$t_{PLZ}$	Propagation Delay LOW Level to HIGH Impedance	$V_{DD} = 5.0\text{V}$		140	280	ns
		$V_{DD} = 10\text{V}$		75	150	
		$V_{DD} = 15\text{V}$		55	110	
$t_{PZH}$	Propagation Delay HIGH Impedance to HIGH Level	$V_{DD} = 5.0\text{V}$		140	280	ns
		$V_{DD} = 10\text{V}$		75	150	
		$V_{DD} = 15\text{V}$		55	110	
$t_{PZL}$	Propagation Delay HIGH Impedance to LOW Level	$V_{DD} = 5.0\text{V}$		140	280	ns
		$V_{DD} = 10\text{V}$		75	150	
		$V_{DD} = 15\text{V}$		55	110	
$t_{THL}$ , $t_{TLH}$	Transition Time	$V_{DD} = 5.0\text{V}$		100	200	ns
		$V_{DD} = 10\text{V}$		50	100	
		$V_{DD} = 15\text{V}$		40	80	
$t_{SU}$	Set-Up Time Data to Clock	$V_{DD} = 5.0\text{V}$	80	40		ns
		$V_{DD} = 10\text{V}$	40	20		
		$V_{DD} = 15\text{V}$	20	10		
$t_r$ , $t_f$	Maximum Clock Rise and Fall Time	$V_{DD} = 5.0\text{V}$	1			ms
		$V_{DD} = 10\text{V}$	1			
		$V_{DD} = 15\text{V}$	1			
$t_{PC}$	Minimum Clock Pulse Width	$V_{DD} = 5.0\text{V}$	200	100		ns
		$V_{DD} = 10\text{V}$	100	50		
		$V_{DD} = 15\text{V}$	83	40		
$t_{PS}$	Minimum Strobe Pulse Width	$V_{DD} = 5.0\text{V}$	200	100		ns
		$V_{DD} = 10\text{V}$	80	40		
		$V_{DD} = 15\text{V}$	70	35		
$f_{max}$	Maximum Clock Frequency	$V_{DD} = 5.0\text{V}$	1.5	3.0		MHz
		$V_{DD} = 10\text{V}$	3.0	6.0		
		$V_{DD} = 15\text{V}$	4.0	8.0		
$C_{IN}$	Input Capacitance	Any Input		5.0	7.5	pF

**Note 5:** AC Parameters are guaranteed by DC correlated testing.

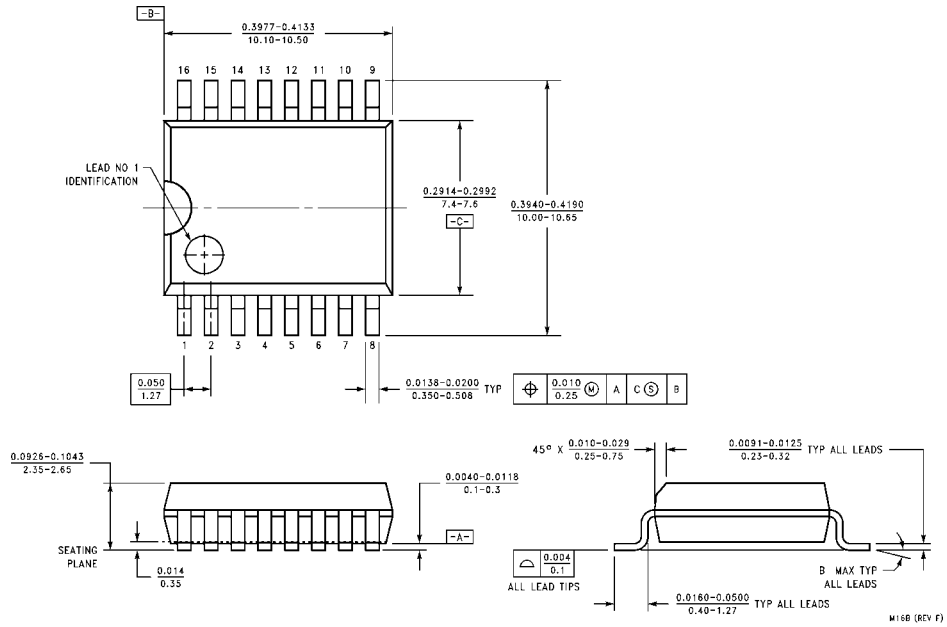
**Timing Diagram**



**Test Circuits and Timing Diagrams for 3-STATE**

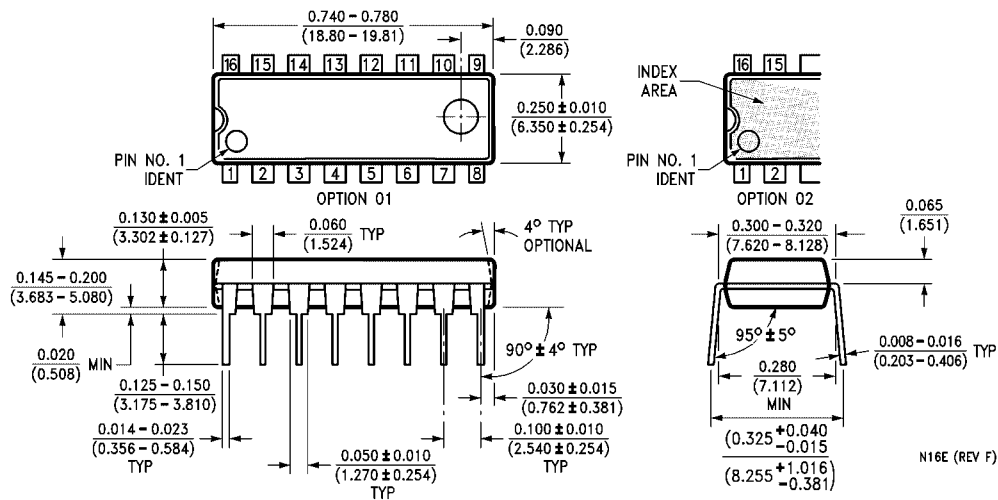


**Physical Dimensions** inches (millimeters) unless otherwise noted



**16-Lead Small Outline Intergrated Circuit (SOIC), JEDEC MS-013, 0.300" Wide  
Package Number M16B**

**Physical Dimensions** inches (millimeters) unless otherwise noted (Continued)



**16-Lead Plastic Dual-In-Line Package (PDIP), JEDEC MS-001, 0.300" Wide  
Package Number N16E**

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